

CORRECTION: In the last issue of this publication we announced a special seminar relating to "Microscopy & Microanalysis Resources on the World Wide Web" to be held just prior to the MSA/MAS/MSC Annual Meeting in Minneapolis this summer.

The correct date for this seminar is Saturday, August 10, 1996, just before the conference starts..

Reservations are strongly recommended, as attendance will be on a first-come-first-served basis. They may be made with the response card in our last issue or by contacting the seminar organizer, John Mansfield, at eMail: jfmjfm@umich.edu

❖ **PITTCON '96**, recently held in Chicago, is reported to be among the most successful ever. Attendance was the largest in history, exceeding the 1990 New York City attendance and verifying the need for a northern city on the Pittsburgh Conference rotation.

Statistics for the conference include:

Conferees Registration: 16,947
 Exhibitor Registration: 17,132
 Total Registration: 34,079
 Exhibiting Companies: 1,116
 Total Booths: 2,949

Future Conference Sites:

Pittcon '97: Atlanta, GA	Pittcon '99: Orlando, FL
Pittcon '98: New Orleans, LA	Pittcon '20: Chicago, IL

❖ **PGT** introduces a new book entitled *X-ray and Image Analysis in Electron Microscopy* by John J. Friel. The purpose of the book is to cover the subjects of X-ray microanalysis and computer-aided imaging at a level that promotes an understanding beyond merely practical texts, but without overwhelming the reader with volume or complexity. It is meant to be an introduction for newcomers to the field and a reference for experienced microscopists. At 94 pages with numerous figures and tables, it is a useful book to keep handy in the microscopy lab. For prices and further information, contact PGT at (609)924-7310, Fax: (609)924-1729.

❖ **Nicolet Instrument Corporation Presents Spectroscopic Solutions Seminar Series**

Nicolet Instrument Corporation launches an all new Spectroscopic Solutions Seminar series for 1996. Each seminar offers innovative solutions for common FT-IR applications such as pharmaceutical, polymer and forensic studies as well as routine analyses like verification and quantification of materials. In addition, each seminar offers an introduction to new technology and information about chemistry on the Internet.

Nicolet's Spectroscopic Solutions Seminar Series runs from April 25 through June 27, 1996 in 26 U.S. cities. Call Nicolet Instrument Corporation at (800)232-1472, ext. 2617 for more information.

❖ **New, Award-Winning NanoTheater™ for Scanning Probe Microscopies.**

Digital Instruments announces the new NanoTheater image forum on the web at www.di.com, as well as their site's "Top 5% of the Web" recognition. The NanoTheater offers over 100 images with explanatory captions in a virtual theater motif. The user begins outside the NanoTheater and enters one of six mini-theaters for Life Sciences, Semiconductors, Atoms and STM, Magnetic Force Microscopy and Data Storage, and general Material Sciences. The sixth theater is a Users' Showcase featuring images contributed by users of NanoScope SPMs. The user then sees the theater lobby and selects from "movie" posters to view a specific image. This brings the user into the virtual theater with the selected image displayed on the "screen" and an explanatory caption. Images are added and rotated on a regular schedule so there is always something new and interesting to view.

For more information, contact Felicia Kashevaroff, Digital Instruments, 520 East Montecito St., Santa Barbara, CA 931103. Tel: 800-873-8950.

❖ **The Histochemical Society**

The Histochemical Society is a non-profit professional organization composed of scientists who employ histochemical and cytochemical techniques in their research. These specialized techniques generally involve the use of labels or stains that allow the definition of parts of the microscopic image of a biological specimen in terms of its specific chemical constituents. Histochemical techniques originally involved light microscopy stains, but more recently have also included electron microscopic techniques, and the detection of enzymatic activities, antigens and specific nucleic acid sequences in individual cells and in tissues. The Society was established in 1950 for scientific purposes to advance and promulgate knowledge concerning the interrelationship of the chemical constitution and detailed morphologic structure of organisms in normal and pathologic states. The Society currently has approximately 500 active members, mostly in North America, with 150 members in other parts of the world. Members of the Society represent many disciplines, including anatomy, pathology, cell biology, biochemistry, immunology, molecular biology and the neurosciences. The Society's primary educational activities include publication of the prestigious *Journal of Histochemistry and Cytochemistry*, and an annual scientific meeting held each summer where symposia, workshops and contributed papers are presented. As a member of the International Federation of Societies for Histochemistry and Cytochemistry, The Histochemical Society actively participates in the International Congress of the Federation held every four years.

The 47th Annual Meeting of the Histochemical Society will be held on 2-3 August, 1996 at the Hyatt Regency Hotel, Bethesda, MD.

For further information:

The Histochemical Society
 4 Barlows Landing Road, Ste 8
 Pocasset, MA 02559
 Phone: (508)563-1155
 Fax: (508)563-1211
 eMail: LMASER@MBL.EDU

❖ **FEI Company Expands.**

The FEI Company recently announced an expansion to increase its plant capacity at its world headquarters in Hillsboro, OR. The new 34,700 sq. ft. facility will be located adjacent to FEI's existing 45,000 sq. ft. manufacturing, R&D and administrative facility located at Hillsboro.

❖ **Tony Carpenter**, previously associated with Oxford/Link Systems, has joined JEOL U.S.A. as District Sales Manager. With offices in Phoenix, his new sales territory includes Arizona, Southern Nevada and Southern California. Tony may be reached at tel.: (602)414-0323.

❖ **Computer-Assisted Image Analysis & Measurement**, a 3-day short course and workshop sponsored by North Carolina State University, will be held on May 16/18 and 20/23, 1996 in Raleigh, NC and on June 17/20, 1996 in Taastrup, Denmark.

The course is intended to familiarize users of image analysis equipment with the fundamental principles and methods available to obtain meaningful results, and to educate laboratory supervisors or research professionals seeking to learn how to use such methods in their applications. The techniques are applicable to fields ranging from materials, geological and biological research to food technology and manufacturing quality control. The course relies heavily on tightly coupled lectures and hands-on experience with the various techniques. The laboratory includes a variety of image analysis programs selected to offer a wide range of approaches and tools, and a detailed set of practical instructions to enable their use with a minimal learning curve.

For further information, contact Belinda Niedwisch, North Carolina State University at (919)515-8185 or Fax: (919)515-7614, or Dr. John Russ at eMail: john_russ@ncsu.edu

Microscopy and Surface Analysis Manufacturers and Suppliers on the WWW

The following is an update to the list in a previous issue of this publication - and will be further updated in the future.

Advanced Surface Technology: <http://www.advsurftech.com>
 Beckman Instruments: <http://www.beckman.com>
 Bruker Instruments, Inc.: <http://www.bruker.com>
 Carl Zeiss: <http://www.ctan.yale.edu/HTML/YALE/CTAN/zeisspg.html>
 Custom Medical Stock Photos: <http://www.cmsp.com>
 Delaware Diamond Knives: <http://www.ddk.com>
 Diatome Diamond Knives: http://www.mwrn.com/page/diatome/dia_995.htm
 Digital Instruments: <http://www.di.com>
 Eastman Kodak: <http://www.kodak.com>
 Energy Beam Sciences: <http://www.mwrn.com/ebs/ebs.html>
 Ernest F. Fullam: <http://www.fullam.com/>
 Fisons Instruments: <http://www.fisonssurf.co.uk>
 Gatan Inc.: <http://www.gatan.com>
 Hitachi Instruments: <http://www.hii.hitachi.com>
 JEOL USA: <http://www.jeol.com>
 Kratos Analytical: <http://www.kratos.com>
 LEO Electron Microscopes: <http://www.mwrn.com/leo/>
 Material Analytical Sciences: <http://www.microstartech.com/>
 Micro Star Technologies: <http://www.microstartech.com/>
 Nanoprobes: <http://www.lihti.org/research/ecodev/incubten/nano/home.html>

Nicolet Instrument Corporation: <http://nicolet.com/>
 Nissie-Sangyo Candad: <http://www.nsctoronto.com/nissei-sangyo>
 Park Scientific Instruments: <http://www.park.com>
 Philips Electronic Instruments: <http://www.peo.philips.com>
 Philips Electron Optics: <http://www.peo.philips.com/>
 Princeton Gamma-Tech: <http://www.pgt.com>
 Scott Scientific: <http://ScottScientific.com>
 SPI Supplies: <http://mail.cccbi.chester.pa.us/spi/spihome.html>
 Thomson Scientific Instruments: <http://werple.net.au/tsi/>
 Topometrix Corporation: <http://www.topometrix.com>
 Vacuum Generators: <http://WWW.surface.fisons.co.uk/vacgen/vg-home.html>
 Vaytek: <http://www.vaytek.com/>
 Virtual Laboratories: <http://www.rt66.com/~virtlabs/>

And a Few of the Others . . .

Directory of Microscopists on the Net: <http://bocklabs.wisc.edu/imr/microscopists.html>
 Electron Microscopy Yellow Pages: <http://cimewww.epfl.ch/emyp/>
 Integrated Microscopy Resources: <http://www.bocklabs.wisc.edu/imr/imr.html>
 Microbeam Analysis Society: http://www.engin.umich.edu/~jfmjfm/mas_folder/mashomepage.html
 Microscopes and Microscopy: <http://metro.turnpike.net/jefferie/index.html>
 Microscopy Online: <http://www.microscopy-online.com/>
 Microscopy Society of America: <http://www.microscopy.com>
 Microworld Resources And News: <http://mwrn.ms.wva.com/topfile.htm>
 Royal Microscopical Society: <http://146.139.72.10/Docs/nonan/rms/rmsinfo.html>
 University of Michigan: <http://www.engin.umich.edu/microscopy/>

KEVEX FLAME™

Fuzzy Logic Automated Microanalysis Engine....

The NEW Macintosh Based EDS Microanalyzer from Kevex Instruments!

Kevex FLAME is a Macintosh based EDS analyzer, affordably priced, offering a flexible architecture and user-friendly GUI. FLAME is available as a retrofit (i.e. upgrading older EDS analyzers) or as a new and complete standalone microanalyzer, which includes:

- **Fuzzy Logic & Artificial Intelligence database**
- **User-definable setups with custom preferences**
- **Image and X-ray map acquisitions up to 4096 pixels**
- **Feature Analysis with comprehensive parameters and Image "Gallery"**



FLAME is a trademarked product developed by xk, Incorporated

Kevex Instruments • 24911 Avenue Stanford • Valencia, CA 91355 • Tel. (805) 295-0019 • Fax (805) 295-8714